

Freeform Search

Database:	US Pre-Grant Publication Full-Text Database US Patents Full-Text Database US OCR Full-Text Database EPO Abstracts Database JPO Abstracts Database Derwent World Patents Index IBM Technical Disclosure Bulletins
Term:	(wafer or substrate) with (jog\$4 or danc\$4)
Display:	<input type="text" value="10"/> Documents in Display Format: <input type="text" value="-"/> Starting with Number <input type="text" value="1"/>
Generate: <input type="radio"/> Hit List <input checked="" type="radio"/> Hit Count <input type="radio"/> Side by Side <input type="radio"/> Image	

Search History

DATE: Monday, May 02, 2005
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<u>Set</u> <u>Name</u>	<u>Query</u>	<u>Hit</u> <u>Count</u>	<u>Set</u> <u>Name</u> result set
side by side			
	<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR</i>		
<u>L15</u>	(wafer or substrate) with (jog\$4 or danc\$4)	286	<u>L15</u>
<u>L14</u>	L13 and (beam with proportional)	320	<u>L14</u>
<u>L13</u>	L7 and proportional	3963	<u>L13</u>
<u>L12</u>	L11 not L10	315	<u>L12</u>
<u>L11</u>	L9 and substrate	946	<u>L11</u>
<u>L10</u>	L9 and wafer	745	<u>L10</u>
<u>L9</u>	L8 and edge	1060	<u>L9</u>
<u>L8</u>	L7 and (beam with parallel)	1980	<u>L8</u>
<u>L7</u>	(wafer or substrate) with (drift or offset or deviat\$4)	31923	<u>L7</u>
<u>L6</u>	L5 and data	700	<u>L6</u>
<u>L5</u>	L4 and ((sensor or detector) with (adjust\$5 or mov\$7))	930	<u>L5</u>
<u>L4</u>	((wafer or substrate) with (deviation or drift or offset)) and ((sensor or detector) with beam)	2178	<u>L4</u>
<u>L3</u>	((block\$4 with beam) same (edge with (substrate or wafer))) and ((beam or block\$3) with proportional with (deviation or position or offset or drift))	2	<u>L3</u>

L2 L1420 L2L1 ((wafer or substrate) with (drift or offset or center)) and ((position\$3 or
mov\$5) with (substrate or wafer)) and (proportional with beam)420 L1

END OF SEARCH HISTORY